

Docket No.: AR-R10-CIP2

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Anton Rodi
CIP of
Applic. No. : 10/200,901, filed July 23, 2002
CIP filed : November 3, 2003
Title : Measuring System for Recording Absolute Angular or Position Values

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner for Patents;
Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. 1.98, copies of the following patents and/or publications are cited herewith:

German Patent No. DE 196 21 015 C2 (Braun), dated November 27, 1997;

German Published, Non-Prosecuted Patent Application No. DE 195 05 176 A1 (Seitz et al.), dated August 31, 1995;

German Published, Non-Prosecuted Patent Application No. DE 197 24 732 A1 (Nelle et al.), dated December 17, 1998;

German Published, Non-Prosecuted Patent Application No. DE 198 21 558 A1 (Tondorf), dated February 11, 1999;

German Utility Model No. G 85 21 160.5 U1, dated March 29, 1990;

German Search Report, dated January 17, 2002.

The above-mentioned references were cited in an Information Disclosure Statement submitted on May 3, 2002, in grandparent application No. 10/116,489.

U.S. Patent No. 2,659,072 (Coales et al.), dated November 10, 1953;

U.S. Patent No. 4,158,509 (Rieder et al.), dated June 19, 1979;

U.S. Patent No. 4,465,373 (Tamaki et al.), dated August 14, 1984;

U.S. Patent No. 4,530,155 (Burkhardt et al.), dated July 23, 1985;

U.S. Patent No. 4,628,609 (Rieder et al.), dated December 16, 1986;

U.S. Patent No. 4,631,404 (Burkhardt et al.), dated December 23, 1986;

U.S. Patent No. 4,786,891 (Ueda et al.), dated November 22, 1988;
U.S. Patent No. 4,793,067 (Reimar et al.), dated December 27, 1988;
U.S. Patent No. 4,996,778 (Rieder et al.), dated March 5, 1991;
U.S. Patent No. 5,115,573 (Rieder et al.), dated May 26, 1992;
U.S. Patent No. 5,793,201 (Nelle et al.), dated August 11, 1998;
U.S. Patent No. 5,894,678 (Masreliez et al.), dated April 20, 1999;
U.S. Patent No. 6,029,118 (Strasser), dated February 22, 2000;
U.S. Patent No. 6,163,970 (Nelle et al.), dated December 26, 2000.

The above-mentioned references were cited in an Office action dated May 22, 2003, in grandparent application No. 10/116,489.

U.S. Patent No. 4,363,964 (Schmitt), dated December 14, 1982;
U.S. Patent No. 4,373,266 (Stutz), dated February 15, 1983;
U.S. Patent No. 4,459,750 (Affa), dated July 17, 1984;
U.S. Patent No. 4,747,215 (Waikas), dated May 31, 1988;
U.S. Patent No. 5,010,655 (Rieder et al.), dated April 30, 1991;
U.S. Patent No. 5,287,630 (Geisler), dated February 22, 1994;
U.S. Patent No. 5,583,798 (Franz et al.), dated December 10, 1996

The above-mentioned references were cited in an Office action dated August 26, 2003, in parent application No. 10/200,901.

Respectfully submitted,



For Applicant

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FORM PTO-1449 (SUBSTITUTE)		Attorney Docket No.: CIP of Applic. No. AR-R10-CIP2 10/200,901	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Applicant Anton Rodi	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		CIP Filing Date November 3, 2003	Group Art Unit 2859

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	2,659,072	11/53	Coales et al.			
	B	4,158,509	06/79	Rieder et al.			
	C	4,465,373	08/84	Tamaki et al.			
	D	4,530,155	07/85	Burkhardt et al.			
	E	4,628,609	12/86	Rieder et al.			
	F	4,631,404	12/86	Burkhardt et al.			
	G	4,786,891	11/88	Ueda et al.			
	H	4,793,067	12/88	Reimar et al.			
	I	4,996,778	03/91	Rieder et al.			

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J	DE 196 21 015 C2	11/97	Germany			
	K	DE 195 05 176 A1	08/95	Germany			
	L	DE 197 24 732 A1	12/98	Germany			
	M	DE 198 21 558 A1	02/99	Germany			
	N	G 85 21 160.5 U1	03/90	Germany			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	D	6,029,118	02/00	Strasser			
	E	6,163,970	12/00	Nelle et al.			
	F	4,363,964	12/82	Schmitt			
	G	4,373,266	02/83	Stutz			
	H	4,459,750	07/84	Affa			
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	B	5,287,630	02/94	Geisler			
	C	5,583,798	12/96	Franz et al.			
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